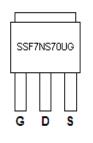
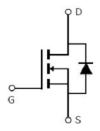


## **Main Product Characteristics:**

V <sub>DSS</sub>	700V
R <sub>DS</sub> (on)	0.7Ω (typ.)
I <sub>D</sub>	<b>7A</b> ①







TO-251 (IPAK)

Marking and Pin
Assignment

Schematic Diagram

## **Features and Benefits:**

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



## **Description:**

The SSF7NS70UG series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

# **Absolute Max Rating:**

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	7①		
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	4.3①	Α	
I <sub>DM</sub>	Pulsed Drain Current ②	21		
D @TC 25°C	Power Dissipation ③	41	W	
P <sub>D</sub> @TC = 25°C	Linear Derating Factor	0.33	W/°C	
V <sub>DS</sub>	Drain-Source Voltage	700	V	
V <sub>GS</sub>	V <sub>GS</sub> Gate-to-Source Voltage		V	
E <sub>AS</sub> Single Pulse Avalanche Energy @ L=100mH		112	mJ	
I <sub>AS</sub>	Avalanche Current @ L=100mH	1.5	А	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C	





## **Thermal Resistance**

Symbol	Characteristics	Тур.	Max.	Units
R <sub>θJC</sub>	Junction-to-case ③	_	3.0	°CM
$R_{\theta JA}$	Junction-to-ambient (t $\leq$ 10s) (4)	_	62	°CM

# **Electrical Characteristics** $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	700	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
		_	0.7	0.85	Ω	V <sub>GS</sub> =10V,I <sub>D</sub> = 1A
D	Static Drain-to-Source on-resistance	_	1.5	_		T <sub>J</sub> = 125°C
$R_{DS(on)}$	Static Diam-to-Source on-resistance	_	0.85	0.95	Ω	$V_{GS}=10V, I_{D}=4.8A$
		_	2.3	_	22	T <sub>J</sub> = 125°C
V	Gate threshold voltage	3	_	5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
$V_{GS(th)}$	Gate threshold voltage		3.3	_	V	T <sub>J</sub> = 125°C
1	Drain to Source leakage ourrent	_	_	1		$V_{DS} = 700 V, V_{GS} = 0 V$
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	50	μΑ	T <sub>J</sub> = 125°C
1	Gate-to-Source forward leakage	_	_	100	nA	V <sub>GS</sub> =30V
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	-100		V <sub>GS</sub> = -30V
$Q_g$	Total gate charge	_	12	_	nC	$I_D = 2.2A,$
$Q_{gs}$	Gate-to-Source charge	_	3.2	_		V <sub>DS</sub> =480V,
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	5.2	_		V <sub>GS</sub> = 10V
t <sub>d(on)</sub>	Turn-on delay time	_	12	_		
t <sub>r</sub>	Rise time	_	8.6	_	ns	$V_{GS}$ =10V, $V_{DS}$ =400V,
t <sub>d(off)</sub>	Turn-Off delay time	_	24	_		$R_{GEN}=10.2\Omega, I_{D}=2.2A$
t <sub>f</sub>	Fall time	_	14	_		
C <sub>iss</sub>	Input capacitance	_	525	_		V <sub>GS</sub> = 0V
Coss	Output capacitance	_	21	_	pF	V <sub>DS</sub> = 100V
C <sub>rss</sub>	Reverse transfer capacitance	_	2.7	_		f = 1MHz

# **Source-Drain Ratings and Characteristics**

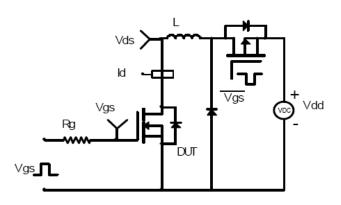
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			7 ①	۸	MOSFET symbol
Is	(Body Diode)	_	_	7 ①	A	showing the
I <sub>SM</sub>	Pulsed Source Current			21	А	integral reverse
	(Body Diode)	_	_			p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	0.85	1.2	V	I <sub>S</sub> =4.8A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	_	132	_	nS	$T_J = 25^{\circ}C, I_F = 2.2A,$
Q <sub>rr</sub>	Reverse Recovery Charge	_	805	_	nC	di/dt = 100A/μs

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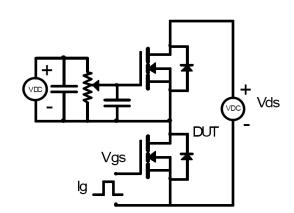


### **Test circuits and Waveforms**

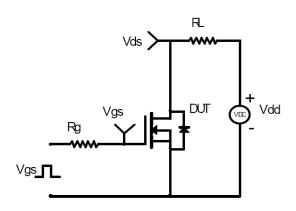
#### **EAS Test Circuit:**



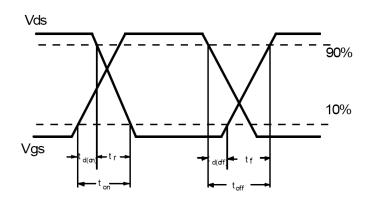
#### Gate charge test circuit:



#### **Switching Time Test Circuit:**



### **Switching Waveforms:**



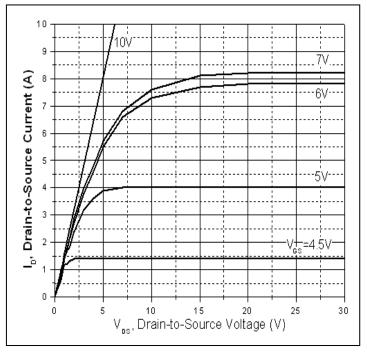
### Notes:

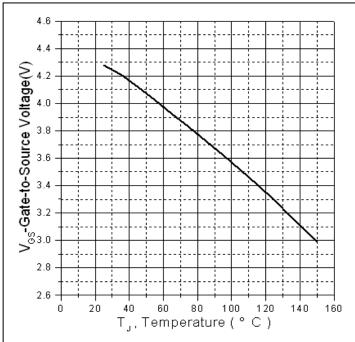
- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of  $R_{\texttt{9JA}}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C





# Typical electrical and thermal characteristics





**Figure 1: Typical Output Characteristics** 

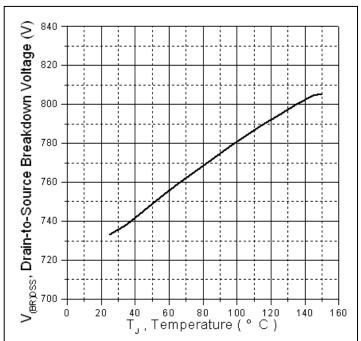


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

Figure 2. Gate to source cut-off voltage

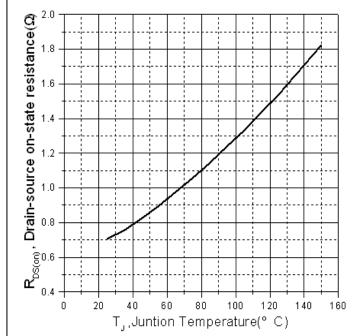


Figure 4: Normalized On-Resistance Vs. Case Temperature ( $V_{GS}=10V,I_D=1A$ )



# Typical electrical and thermal characteristics

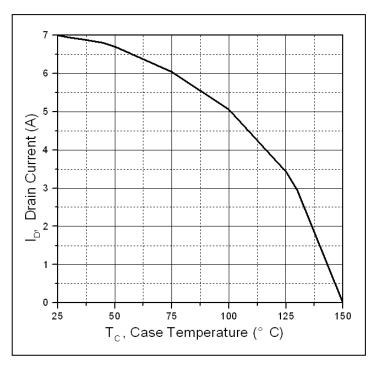


Figure 5. Maximum Drain Current Vs. Case Temperature

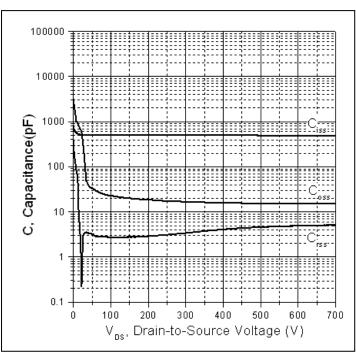


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage

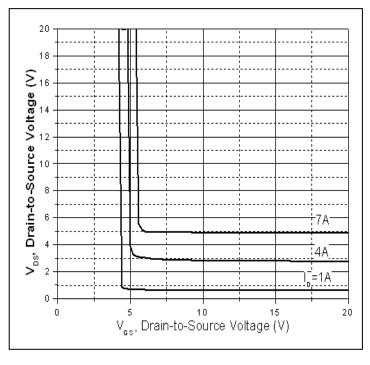


Figure 7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage

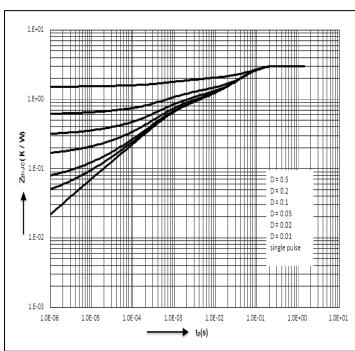
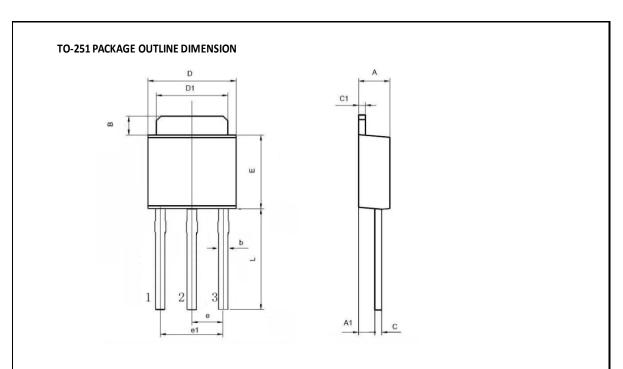


Figure8. Maximum Effective Transient Thermal Impedance, Junction-to-Case



## **Mechanical Data:**



Symbol	Dimens	ion In Mill	imeters	Dimension In Inches		
Symbol	Min	Nom	Max	Min	Nom	Max
Α	2.200	-	2.400	0.087	-	0.094
A1	0.950	•	1.150	0.037	-	0.045
В	0.950	•	1.250	0.037	-	0.049
b	0.500	-	0.700	0.020	-	0.028
С	0.450	•	0.550	0.018	-	0.022
c1	0.450	•	0.550	0.018	-	0.022
D	6.450	•	6.750	0.254	-	0.266
D1	5.200	•	5.400	0.205	-	0.213
Е	5.950	•	6.250	0.234	-	0.246
е	2.240	-	2.340	0.088	-	0.092
e1	4.430	-	4.730	0.174	-	0.186
L	9.000	-	9.400	0.354	-	0.370





# **Ordering and Marking Information**

**Device Marking: SSF7NS70UG** 

Package (Available)
TO-251(IPAK)
Operating Temperature Range
C: -55 to 150 °C

# **Devices per Unit**

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
				Box	

# **Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High	T <sub>j</sub> =150℃ @ 80% of	168 hours	3 lots x 77 devices
Temperature	Max V <sub>DSS</sub> /V <sub>CES</sub> /VR	500 hours	
Reverse		1000 hours	
Bias(HTRB)			
High	T <sub>j</sub> =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V <sub>GSS</sub>	500 hours	
Gate		1000 hours	
Bias(HTGB)			

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